

PCN# 20210326003.1 Transfer of select C10 devices from ANAM-1 to DMOS5 Wafer Fab site Change Notification / Sample Request

Date:March 31, 2021To:TOKYO ELECTRON DEVICE (DSTR) PCN

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

Texas Instruments requires acknowledgement of receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If samples or additional data are required, requests must be received within **30 days** of this notification.

The changes discussed within this PCN will not take effect any earlier than the proposed first ship date on Page 3 of this notification, unless customer agreement has been reached on an earlier implementation of the change.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice or to provide acknowledgement of this PCN, you may contact your local Field Sales Representative or the PCN Team (<u>PCN ww admin team@list.ti.com</u>). For sample requests or sample related questions, contact your local Field Sales Representative.

PCN Team SC Business Services

Products Affected:

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

DEVICE

CDCLVD1204RGTR CDCLVD1204RGTT

CUSTOMER PART NUMBER null

null

Technical details of this Product Change follow on the next page(s).

PCN Number: 20			210326003.1					Ρ	PCN Date: Mar 31, 2021			
Title: Transfer of select C10 devices from ANAM-1 to DMOS5 Wafer Fab site												
Customer Contact:		PCN Manager				Dept:			Qu	Quality Services		
Proposed 1 st Ship Date:						Estimated Sample Availability:				Date provided at sample request.		
Change 1	vpe:											-
	nbly Site	9		Assemb	ly Pr	ocess	ess			Assembly Materials		
Design		Electrical Speci							Mecha			
Test Site		Packing/Shippi			ping,				Test P			
Wafer Bump Site		Wafer Bump Ma			Mate	aterial			Wafer Bump Process		SS	
Wafer Fab Site			Wafer Fab Materials							Wafer	Fab Process	
			Part number change									
PCN Details												
	Description of Change:											
			from ANAM-1 has been discontinued of this change notification.				discontinue ation.	Transfer to Location)				
Curr	ent Fab	Fab	-				New Fab			b	Wafer	
	Site Proce			Diam			Site		Process		Diameter	
AN	ANAM-1 C10			200	mm		DMOS5 C10			0) 200mm	
Qual details are provided in the Qual Data Section. Reason for Change: Discontinued Fab support from ANAM-1												
Discontinued Fab support from ANAM-1												
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):												
	None											
Changes to product identification resulting from this PCN: Current												
-	Chip Site Chip Site		Origi	in (20L)	Chi	Chip Site Country Code			21L	_)	Chip Site Ci	ty
ANA	ANAM-1		ANM			KOR					Bucheon-si	
New Fal												
	Chip Site Chip Site		-	in (20L)	Chi	Chip Site Country Code			e (21L)		Chip Site Ci	ty
DP10	DP1DM5)M5			USA					Dallas	
Sample product shipping label (not actual product label) TEXAS INSTRUMENTS MADE IN: Malaysia 20: MSL 2 /260C/1 YEAR SEAL DT 03/29/04 OPT: ITEM: SA (L)T0:1750 (not actual product label) (1P) SN74LS07NSR (Q) 2000 (D) 0336 (31T) LOT: 3959047MLA (4W) TKY (1T) 7523483S12 (P) 21L) CCO:USA (21L) CCO:USA (21L) CCO:USA (21L) CCO:USA												
Product /	Affected	Group:										
CDCLVD1204RGTR CDC			CDCLVE CDCLVE				LVD2108RGZ	D2108RGZR CDCLVD21				

Qualification Report

Approve Date 23-March-2021

Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: CDCLVD2108RGZ	Qual Device: CDCLVD1204RGT	QBS Reference: TLK2500IRCP	QBS Reference: TLK2201BIRCP	
AC	Autoclave 121C, 2atm	96 Hours	-	-	3/231/0	3/231/0	
CDM	ESD - CDM	1500 V	-	-	-	1/3/0	
ED	Electrical Characterization	Per Data Sheet Parameters	-	-	Pass	Pass	
HAST	Biased HAST, 130C/85%RH	96 Hours	-	-	3/231/0	-	
HBM	ESD - HBM	4000 V	-	-	-	1/3/0	
HTOL	Life Test, 155C	240 Hours	-	-	3/231/0	-	
HTSL	High Temp. Storage Bake, 170C	420 Hours	-	-	3/135/0	3/135/0	
LU	Latch-up	(Per JESD78)	-	-	-	1/6/0	
T/C	Temp Cycle -65C/150C 500 Cycles		-	-	-	3/231/0	
WBP	Bond Pull	Wires	Pass	Pass	-	-	
WPS	Ball Bond Shear	Wires	Pass	Pass	-	-	
Qual Devic	es qualified at LEVEL3-2600	CDCLVD2108RGZ					

- Qual Devices gualified at LEVEL2-260C: CDCLVD1204RGT

- QBS: Qual By Similarity

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

For guestions regarding this notice, e-mails can be sent to the regional contacts shown below, or you can contact your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
WW PCN Team	PCN ww admin team@list.ti.com

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